

| L<br>Number | Hits | Search Text   | DB  | Time stamp          |
|-------------|------|---|---|---------------------|
| 1           | 65   | (array and substrate and inspection).ti.                              | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/02/04<br>10:37 |
| 2           | 19   | array and substrate and inspection and<br>lcd and capacitor adj4 line | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM TDB | 2003/02/04<br>10:38 |